## Notice of References Cited Application/Control No. 10/645,697 Examiner Betsy L. Deppe Applicant(s)/Patent Under Reexamination BLESSENT ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0176438 A1	11-2002	Karjalainen, Miia	370/441
*	В	US-6,646,979	11-2003	Chen et al.	370/208
*	С	US-7,012,886	03-2006	Meier et al.	370/209
*	D	US-7,020,176	03-2006	Heo, Won-Suk	375/130
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-		-	
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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